



## Freeform Search

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Term:	L7 not 16	 
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### Search History

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side by side			
	DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=ADJ		
<u>L8</u>	L7 not 16	1	<u>L8</u>
<u>L7</u>	11 and 15	8	<u>L7</u>
<u>L6</u>	12 and L5	7	<u>L6</u>
<u>L5</u>	707/\$.ccls.	30172	<u>L5</u>
<u>L4</u>	L2 and model\$	17	<u>L4</u>
<u>L3</u>	L2 and (error\$ near5 detect\$)	8	<u>L3</u>
<u>L2</u>	L1 and (match\$ or compar\$)	154	<u>L2</u>
<u>L1</u>	((first adj (user or client or customer or terminal)) and (second adj (user or client or customer or terminal)) and (change or cop\$ or backup or back-up or modif\$)).ab.	782	<u>L1</u>

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IEE JNL	IEE Journal or Magazine
IEEE CNF	IEEE Conference Proceeding
IEE CNF	IEE Conference Proceeding
IEEE STD	IEEE Standard

Display Format: ☒ Citation ☐ Citation & Abstract**No results were found.**

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